

Qualification Data for the 2um CMOS process at ADLK

QUALIFICATION RESULTS 48-LFCSP			
TEST	CONDITIONS	SAMPLE SIZE (LOT/QTY)	RESULTS
Early Life Failure (ELF)	AEC-Q100-008	3 x 800	Pass
Early Life Failure (ELF)	MIL-STD-883, Method 1015	3 x 667	Pass
High Temperature Operating Life (HTOL)	JESD22-A108, 125°C<Tj<135°C, Biased, 1,000 Hours	9 x 77	Pass
Biased HAST *	JESD22-A110, 130°C, 85% RH, 96hrs	3 x 77	Pass
High Temperature Storage Life	JESD22-A103, 150°C, 1000hrs	6 x 77	Pass
Electrostatic Discharge (ESD) Field Induced Charged Device Model (FICDM)	JESD22-C101, >1500V	-	Pass
Electrostatic Discharge (ESD) Human Body Model (HBM)	ANSI/ESDA/JEDEC JS-001-2010 >8000V	-	Pass
Electrostatic Discharge (ESD) Machine Model (MM)	JESD22-A115 >400V	-	Pass

\*Preconditioned per JEDEC/IPC J-STD-020 MSL 1